

#### FEATURES

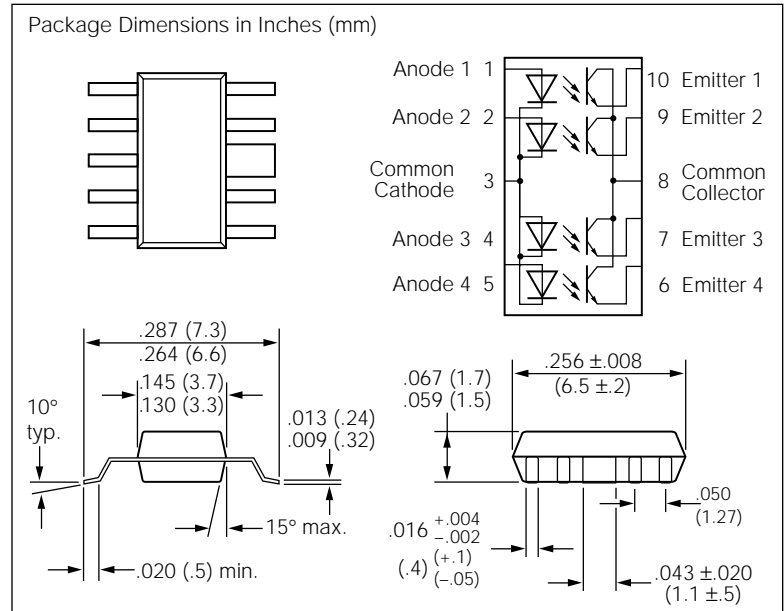
- Transistor Optocoupler in SOT223 Package
- End Stackable, 1.27 mm Spacing
- Low Current Input
- Very High CTR, 150% Typical at  $I_F=1$  mA,  $V_{CE}=0.5$  V
- Good CTR Linearity Versus Forward Current
- Minor CTR Degradation
- Field Effect Stable by TRIOS® (TRansparent IO n Shield)
- High Collector-Emitter Voltage,  $V_{CEO}=70$  V
- Low Coupling Capacitance
- High Common Mode Transient Immunity
- Isolation Test Voltage: 2500 VDC

#### APPLICATIONS

- Telecommunication
- SMT
- PCMCIA
- Instrumentation

#### DESCRIPTION

The SFH6941 is a four channel mini-optocoupler suitable for high density packaged PCB application. It has a minimum of 2500 VDC isolation from input to output. The device consists of four phototransistors as detectors. Each channel is individually controlled. The optocoupler is housed in a SOT223 package. All the cathodes of the input LEDs and all the collectors of the output transistors are commoned enabling a pin count reduction from 16 pins to 10 pins—a significant space savings as compared to four channels that are electrically isolated individually.



#### Absolute Maximum Ratings

##### Emitter (GaAlAs)

Reverse Voltage .....	3 V
DC Forward Current .....	5 mA
Surge Forward Current ( $t_p \leq 10 \mu s$ ) .....	100 mA
Total Power Dissipation .....	10 mW

##### Detector (Si Phototransistor)

Collector-Emitter Voltage .....	70 V
Emitter-Collector Voltage .....	7 V
Collector Current .....	10 mA
Surge Collector Current ( $t_p < 1$ ms) .....	20 mA
Total Power Dissipation .....	20 mW

#### Package Insulation

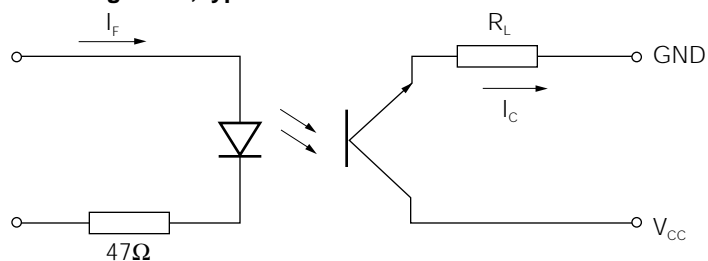
Isolation Test Voltage (between emitter and detector, refer to climate DIN 40046, part 2, Nov. 74) .....	2500 VDC
Creepage .....	$\geq 4$ mm
Clearance .....	$\geq 4$ mm
Comparative Tracking Index per DIN IEC 112/VDE0303, part 1 .....	175
Isolation Resistance	
$V_{IO}=100$ V, $T_A=25^\circ C$ .....	$\geq 10^{11} \Omega$
$V_{IO}=100$ V, $T_A=100^\circ C$ .....	$\geq 10^{10} \Omega$
Storage Temperature Range .....	$-55$ to $+150^\circ C$
Ambient Temperature Range .....	$-55$ to $+100^\circ C$
Junction Temperature .....	$100^\circ C$
Soldering Temperature ( $t=10$ sec. max.) .....	$260^\circ C$
Dip soldering plus reflow soldering processes	

**Characteristics** ( $T_A=25^\circ\text{C}$ , unless otherwise specified)

Description	Symbol	Min.	Typ.	Max.	Unit
<b>Emitter (IR GaAs)</b>					
Forward Voltage, $I_F=5\text{ mA}$	$V_F$		1.25		V
Reverse Current, $V_R=3\text{ V}$	$I_R$		0.01	10	$\mu\text{A}$
Capacitance, $V_R=0\text{ V}$ , $f=1\text{ MHz}$	$C_0$		5		pF
Thermal Resistance	$R_{thJA}$		1000		$^\circ\text{K/W}$
<b>Detector (Si Phototransistor)</b>					
Collector-Emitter Voltage, $I_{CE}=10\ \mu\text{A}$	$V_{CEO}$	70			V
Emitter-Collector Voltage, $I_{EC}=10\ \mu\text{A}$	$V_{ECO}$	7			V
Capacitance, $V_{CE}=5\text{ V}$ , $f=1\text{ MHz}$	$C_{CE}$		6		pF
Thermal Resistance	$R_{thJA}$		500		$^\circ\text{K/W}$
<b>Package</b>					
Coupling Capacitance	$C_C$		1		pF

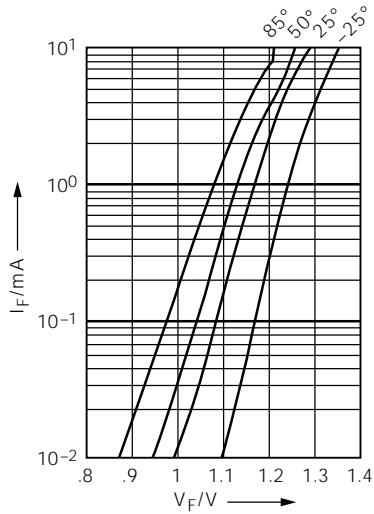
Description	Symbol	Values			Unit
		-3	-4	-5	
Coupling Transfer Ratio $I_F=1\text{ mA}$ , $V_{CE}=0.5\text{ V}$ $I_F=0.5\text{ mA}$ , $V_{CE}=1.5\text{ V}$	$I_C/I_F$ $I_C/I_F$	100–200 120 ( $\geq 50$ )	160–320 200 ( $\geq 80$ )	250–500 300 ( $\geq 125$ )	%
Collector-Emitter Saturation Voltage $I_F=1\text{ mA}$	$V_{CEsat}$	0.25 ( $\leq 0.4$ ) ( $I_C=0.5\text{ mA}$ )	0.25 ( $\leq 0.4$ ) ( $I_C=0.8\text{ mA}$ )	0.25 ( $\leq 0.4$ ) ( $I_C=1.25\text{ mA}$ )	V
Collector-Emitter Leakage Current $V_{CE}=10\text{ V}$	$I_{CEO}$	50	50	50	nA

**Switching times, typical**

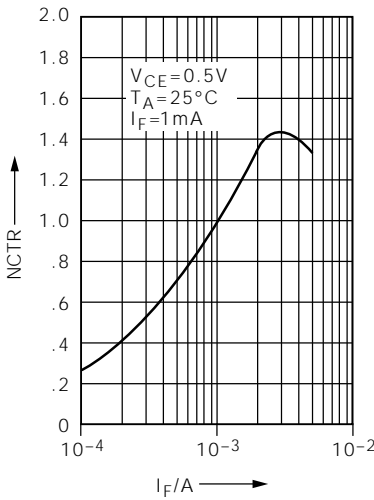


Description	Symbol	Values	Unit	Test Conditions
Turn-on Time	$t_{on}$	3	$\mu\text{s}$	$I_F=2\text{ mA}$ $R_L=100\ \Omega$ $T_A=25^\circ\text{C}$ $V_{CC}=5\text{ V}$
Rise Time	$t_r$	2.6		
Turn-off Time	$t_{off}$	3.1		
Fall Time	$t_f$	2.8		

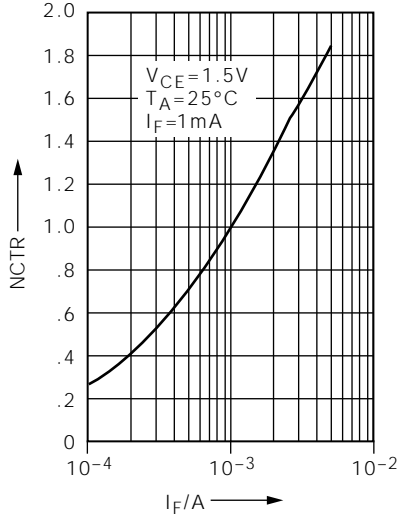
**Figure 1. LED current versus LED voltage  $V_F=f(I_F)$**



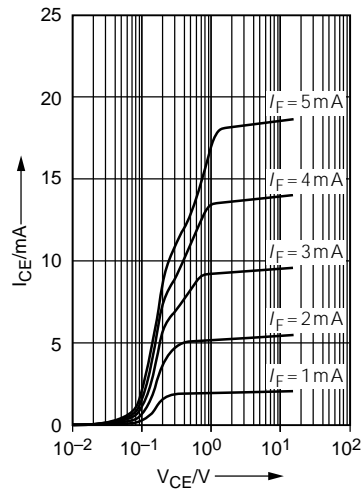
**Figure 2. Saturated current transfer ratio normalized to  $I_F=1$  mA,  $NC-TR=f(I_F)$**



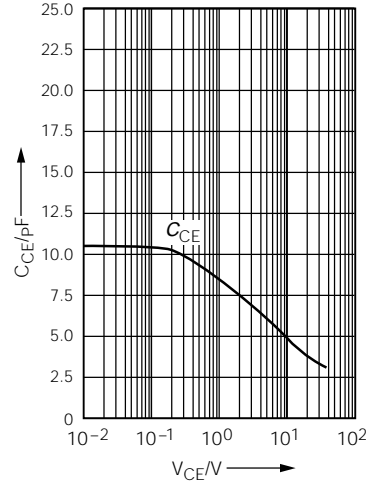
**Figure 3. Non-saturated current transfer ratio normalized to  $I_F=1$  mA,  $NC-TR=f(I_F)$**



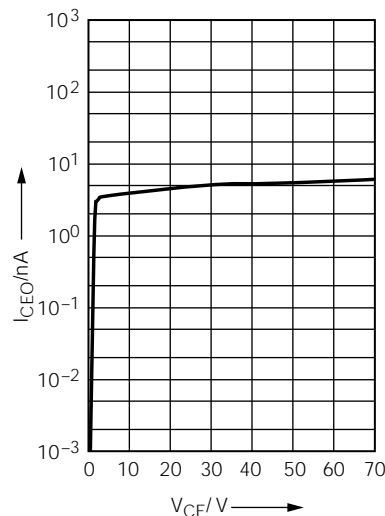
**Figure 4. Transistor output characteristics  $T_A=25^\circ\text{C}$ ,  $I_{CE}=f(V_{CE}, I_F)$**



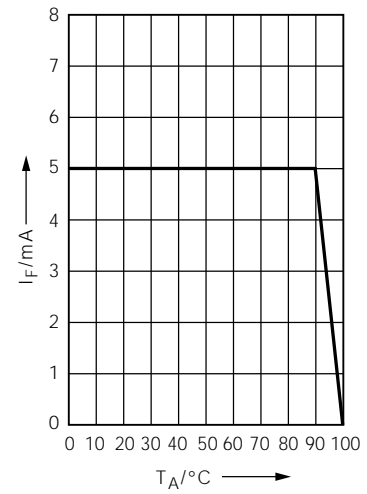
**Figure 5. Transistor capacitance (typ.)  $T_A=25^\circ\text{C}$ ,  $f=1\text{MHz}$ ,  $C_{CE}=f(V_{CE})$**



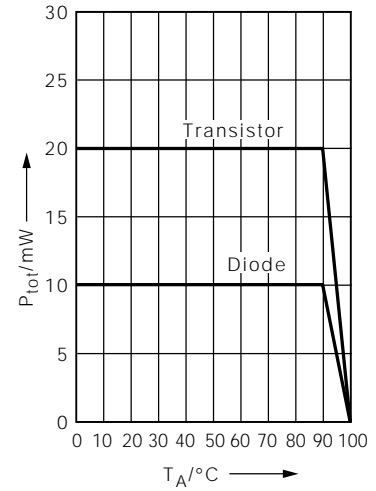
**Figure 6. Collector-emitter leakage current (typ.)  $I_F=0$ ,  $T_A=25^\circ\text{C}$ ,  $I_{CE0}=f(V_{CE})$**



**Figure 7. Permissible forward current diode  $I_F=f(T_A=25^\circ\text{C})$**



**Figure 8. Permissible power dissipation  $P_{tot}=f(T_A)$**



**Figure 9.  $T_A=25^\circ\text{C}$ ,  $I_F=1$  mA,  $V_{CC}=5$  V,  $t_{on}$ ,  $t_r$ ,  $t_{off}$ ,  $t_t=f(R_L)$**

